

**Notice of References Cited**

Application/Control No.

10/589,722

Applicant(s)/Patent Under  
Reexamination  
KAWAHITO, SHOJI

Examiner

ARDESHIR EFTEKHARZADEH

Art Unit

2815

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,136,292 A	01-1979	Suzuki et al.	327/52
*	B	US-6,396,570 B2	05-2002	Takayanagi et al.	356/5.01
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bellutti et al, Microelectronics Reliability 39 (1999) 181-185
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.